

### General Description

The AO4614B uses advanced trench technology MOSFETs to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs may be used in H-bridge, Inverters and other applications.

### Product Summary

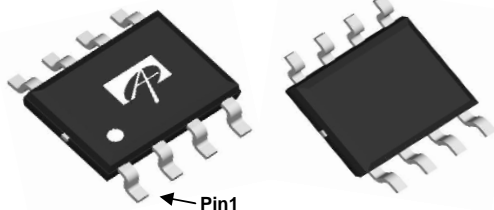
N-Channel	P-Channel
$V_{DS} (V) = 40V,$	-40V
$I_D = 6A (V_{GS}=10V)$	-5A ( $V_{GS}=-10V$ )
$R_{DS(ON)}$	
< 30m $\Omega$ ( $V_{GS}=10V$ )	< 45m $\Omega$ ( $V_{GS}= -10V$ )
< 38m $\Omega$ ( $V_{GS}=4.5V$ )	< 63m $\Omega$ ( $V_{GS}= -4.5V$ )
100% UIS Tested	100% UIS Tested
100% Rg Tested	100% Rg Tested



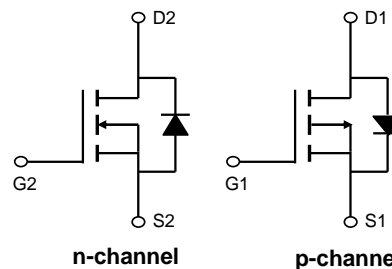
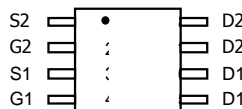
SOIC-8

Top View

Bottom View



Top View



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units	
Drain-Source Voltage	$V_{DS}$	40	-40	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V	
Continuous Drain Current <sup>A</sup>	$I_D$	$T_A=25^\circ\text{C}$	6	-5	A
		$T_A=70^\circ\text{C}$	5	-4	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	-30		
Avalanche Current <sup>B</sup>	$I_{AR}$	14	-20		
Repetitive avalanche energy $L=0.1\text{mH}$ <sup>B</sup>	$E_{AR}$	9.8	20	mJ	
Power Dissipation	$P_D$	$T_A=25^\circ\text{C}$	2	2	W
		$T_A=70^\circ\text{C}$	1.28	1.28	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	$^\circ\text{C}$	

### Thermal Characteristics: n-channel and p-channel

Parameter	Symbol	Device	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	n-ch	48	62.5	$^\circ\text{C/W}$
Maximum Junction-to-Ambient <sup>A</sup>		n-ch	74	110	$^\circ\text{C/W}$
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	n-ch	35	50	$^\circ\text{C/W}$
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	p-ch	48	62.5	$^\circ\text{C/W}$
Maximum Junction-to-Ambient <sup>A</sup>		p-ch	74	110	$^\circ\text{C/W}$
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	p-ch	35	50	$^\circ\text{C/W}$

**N Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	40			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=40\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.7	2.5	3	V
$I_{D(ON)}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=6\text{A}$ $T_J=125^\circ\text{C}$ $V_{GS}=4.5\text{V}, I_D=5\text{A}$		24 36 30	30 45 38	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=6\text{A}$		19		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.76	1	V
$I_S$	Maximum Body-Diode Continuous Current				2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=20\text{V}, f=1\text{MHz}$	410	516	650	pF
$C_{oss}$	Output Capacitance			82		pF
$C_{rss}$	Reverse Transfer Capacitance			43		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		4.6		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=20\text{V},$ $I_D=6\text{A}$		8.9	10.8	nC
$Q_g(4.5\text{V})$	Total Gate Charge			4.3	5.6	nC
$Q_{gs}$	Gate Source Charge			2.4		nC
$Q_{gd}$	Gate Drain Charge			1.4		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=20\text{V}, R_L=3.3\Omega,$ $R_{GEN}=3\Omega$		6.4		ns
$t_r$	Turn-On Rise Time			3.6		ns
$t_{D(off)}$	Turn-Off DelayTime			16.2		ns
$t_f$	Turn-Off Fall Time			6.6		ns
$t_{rr}$	Body Diode Reverse Recovery Time		$I_F=6\text{A}, dl/dt=100\text{A}/\mu\text{s}$		18	24
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=6\text{A}, dl/dt=100\text{A}/\mu\text{s}$		10		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

Rev2 : Nov. 2010

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CHANNEL

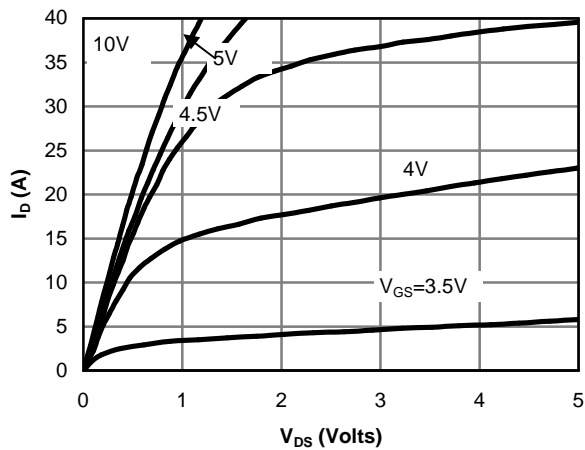


Fig 1: On-Region Characteristics

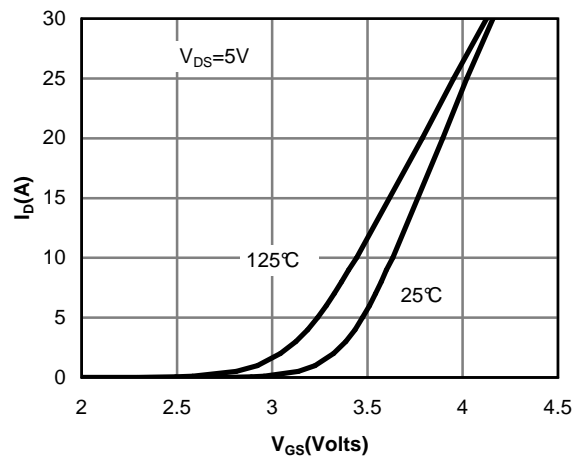


Figure 2: Transfer Characteristics

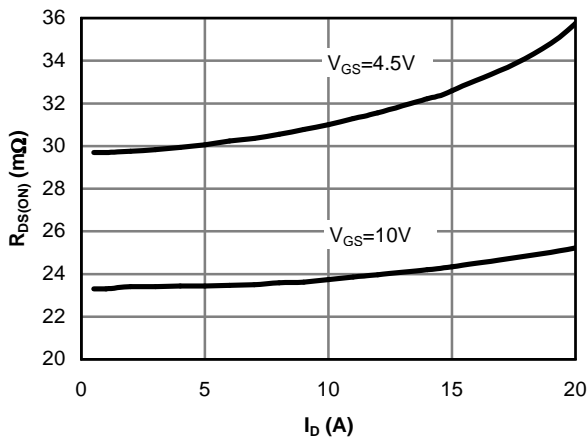


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

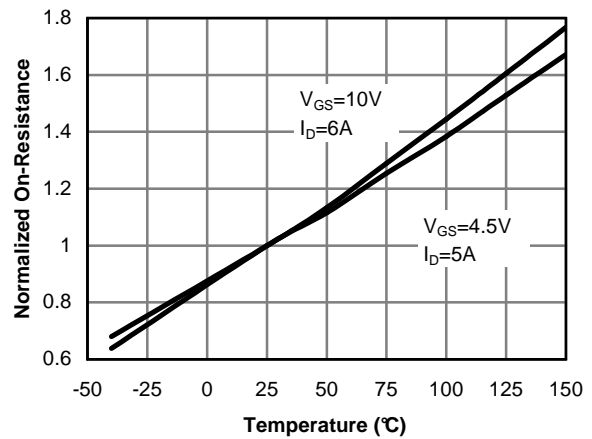


Figure 4: On-Resistance vs. Junction Temperature

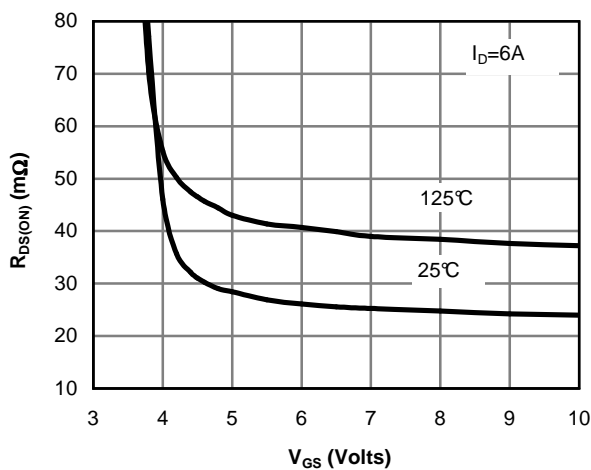


Figure 5: On-Resistance vs. Gate-Source Voltage

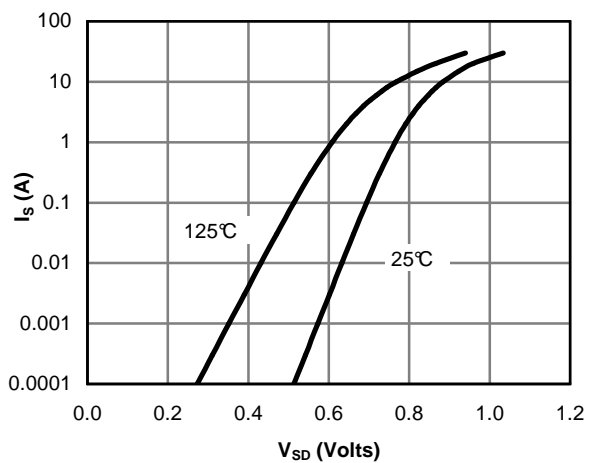


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CHANNEL

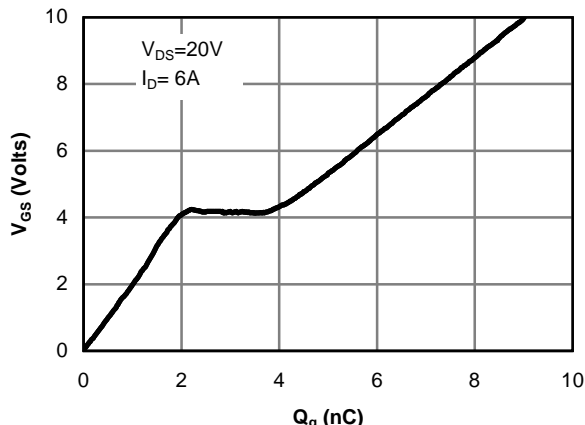


Figure 7: Gate-Charge Characteristics

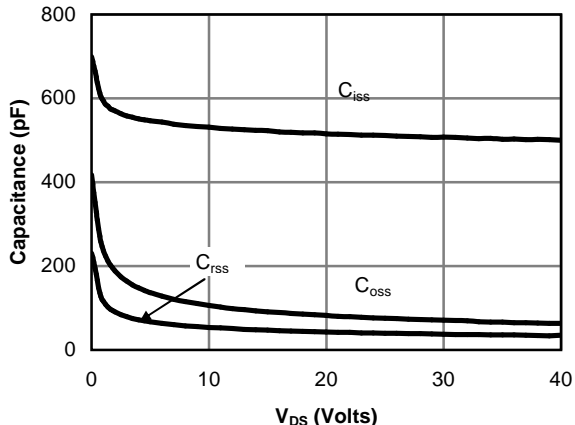


Figure 8: Capacitance Characteristics

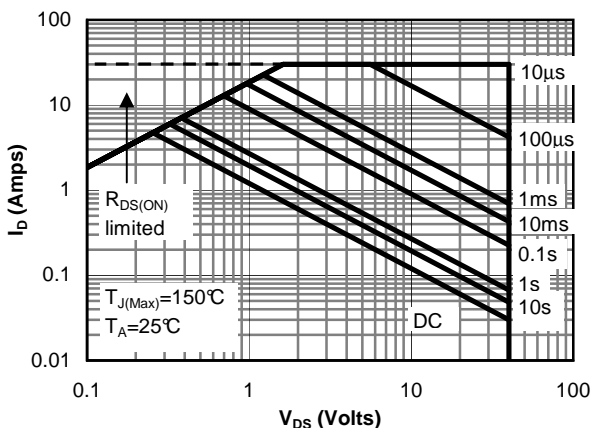


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

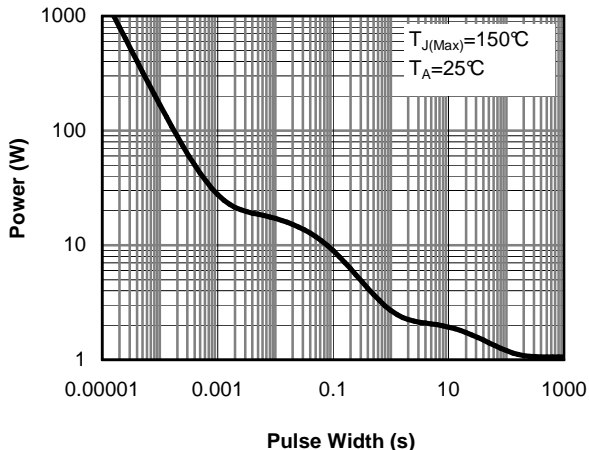


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

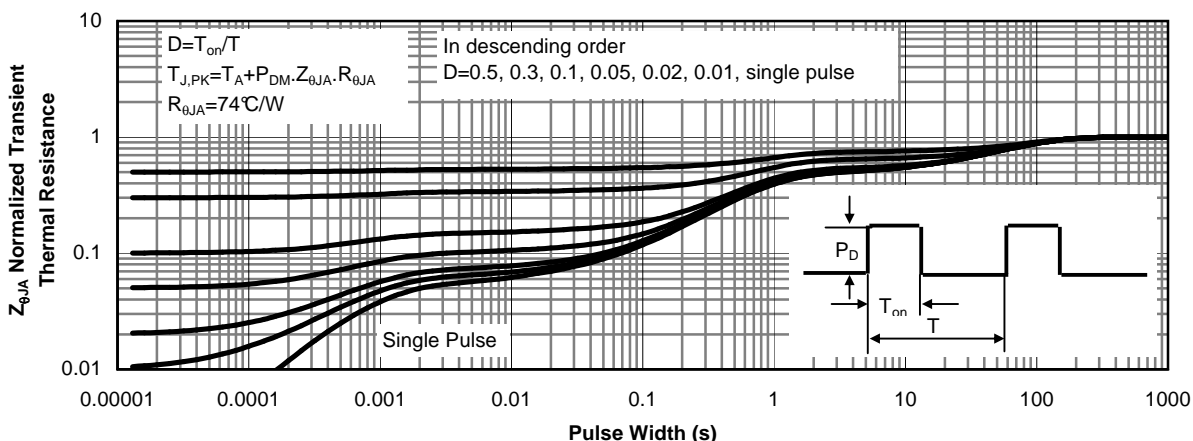


Figure 11: Normalized Maximum Transient Thermal Impedance

**P-Channel Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
B <sub>V</sub> DSS	Drain-Source Breakdown Voltage	I <sub>D</sub> = -250μA, V <sub>GS</sub> =0V	-40			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -40V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			-1 -5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> I <sub>D</sub> = -250μA	-1.7	-2	-3	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -5V	-30			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10V, I <sub>D</sub> = -5A T <sub>J</sub> =125°C V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -4A		36 52 50	45 65 63	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -5V, I <sub>D</sub> = -5A		13		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> = -1A, V <sub>GS</sub> =0V		-0.76	-1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				-2	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> = -20V, f=1MHz	750	940	1175	pF
C <sub>oss</sub>	Output Capacitance		97			pF
C <sub>rss</sub>	Reverse Transfer Capacitance		72			pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		14		Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub> (-10V)	Total Gate Charge	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -20V, I <sub>D</sub> = -5A		17	22	nC
Q <sub>g</sub> (-4.5V)	Total Gate Charge		7.9	10	nC	
Q <sub>gs</sub>	Gate Source Charge		3.4		nC	
Q <sub>gd</sub>	Gate Drain Charge		3.2		nC	
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -20V, R <sub>L</sub> =4Ω, R <sub>GEN</sub> =3Ω		6.2		ns
t <sub>r</sub>	Turn-On Rise Time		8.4		ns	
t <sub>D(off)</sub>	Turn-Off DelayTime		44.8		ns	
t <sub>f</sub>	Turn-Off Fall Time		41.2		ns	
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> = -5A, di/dt=100A/μs		21	27	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> = -5A, di/dt=100A/μs		14		nC

A: The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R<sub>θJA</sub> is the sum of the thermal impedance from junction to lead R<sub>θJL</sub> and lead to ambient.

D: The static characteristics in Figures 1 to 6,12,14 are obtained using <300 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating .

Rev1 : Jan 2010

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

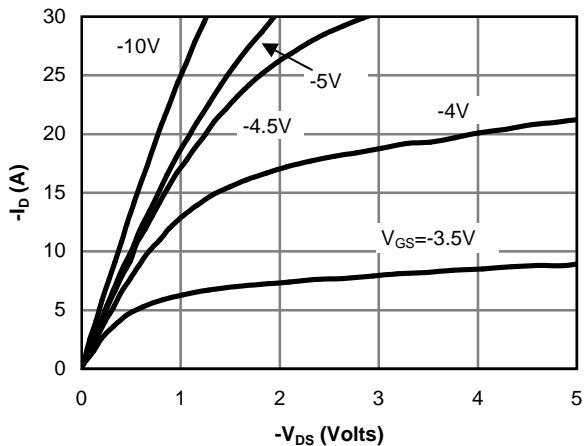


Fig 12: On-Region Characteristics

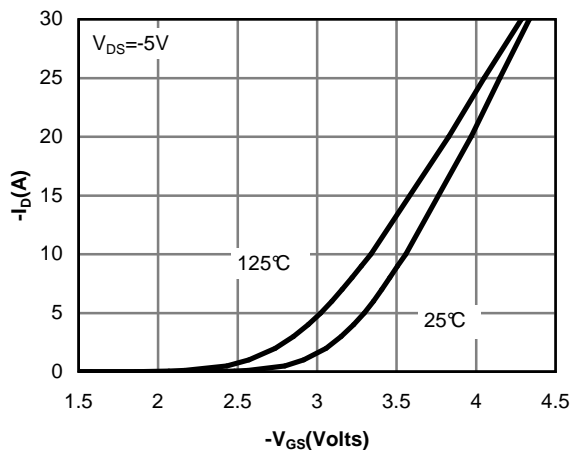


Figure 13: Transfer Characteristics

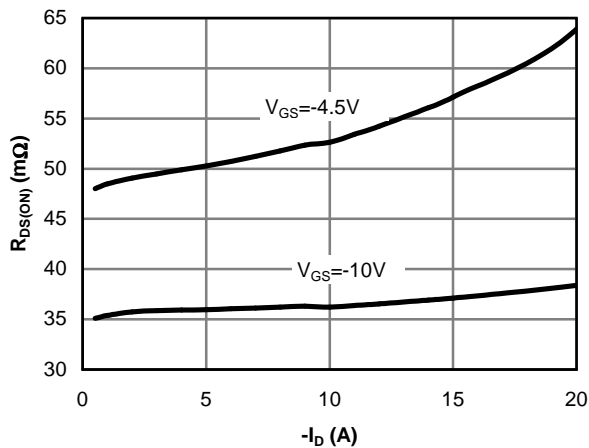


Figure 14: On-Resistance vs. Drain Current and Gate Voltage

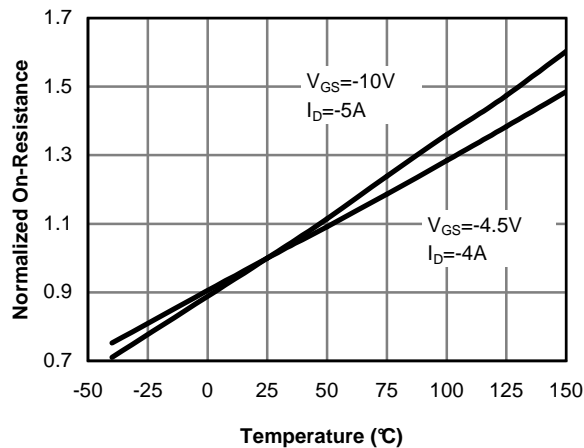


Figure 15: On-Resistance vs. Junction Temperature

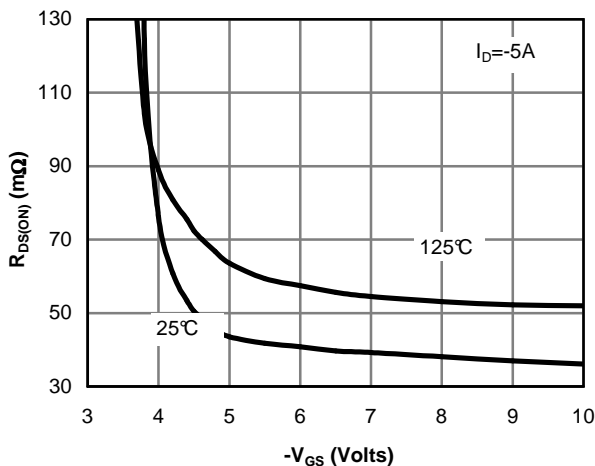


Figure 16: On-Resistance vs. Gate-Source Voltage

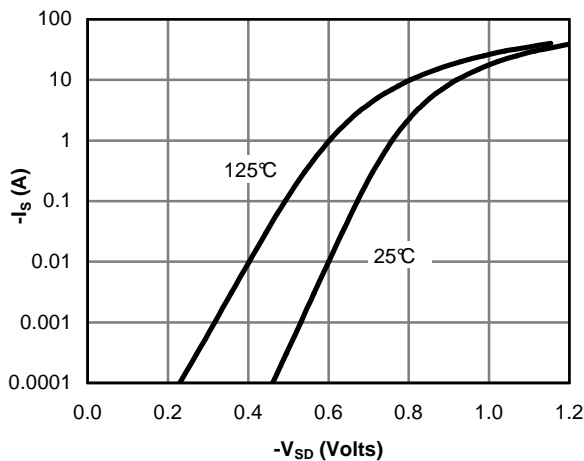


Figure 17: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

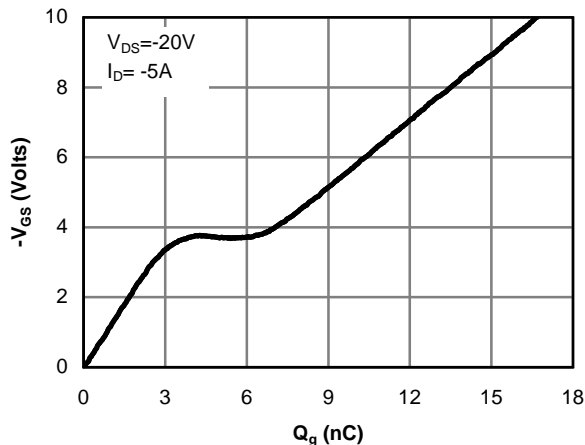


Figure 18: Gate-Charge Characteristics

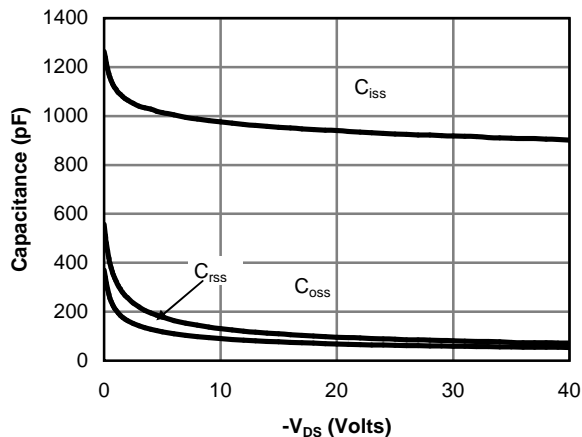


Figure 19: Capacitance Characteristics

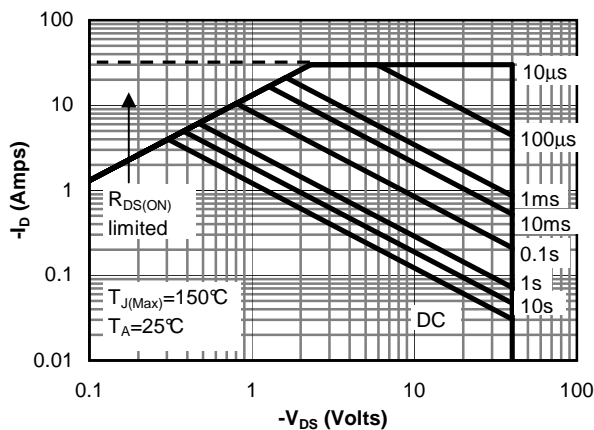


Figure 20: Maximum Forward Biased Safe Operating Area (Note E)

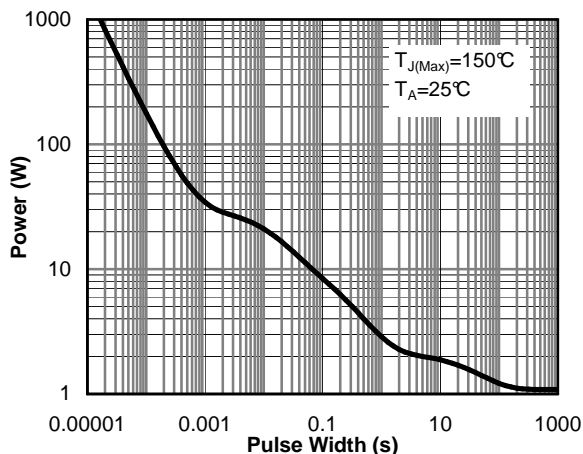


Figure 21: Single Pulse Power Rating Junction-to-Ambient (Note E)

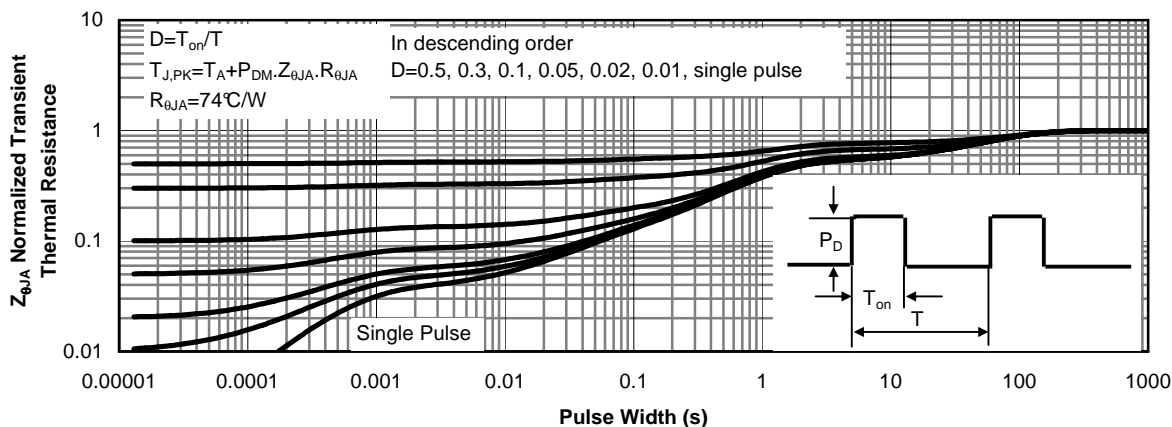


Figure 22: Normalized Maximum Transient Thermal Impedance